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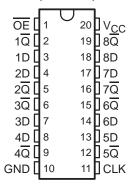
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C
- High-Drive Outputs (-32-mA I_{OH}, 64-mA I_{OL})
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Plastic (N) and Ceramic (J) DIPs, and Ceramic Flat (W) Package

description

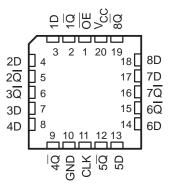
These 8-bit flip-flops with 3-state outputs are designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight flip-flops are edge-triggered D-type flip-flops. On the positive transition of the clock (CLK), the \overline{Q} outputs are set to the complement of the logic levels set up at the data (D) inputs.

SN54ABT534...J OR W PACKAGE SN74ABT534A...DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54ABT534 . . . FK PACKAGE (TOP VIEW)



A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

 $\overline{\text{OE}}$ does not affect the internal operations of the flip-flop. Previously stored data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT534 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74ABT534A is characterized for operation from -40° C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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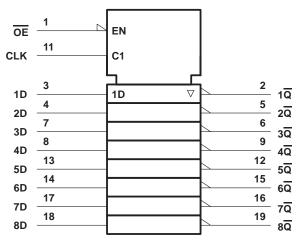


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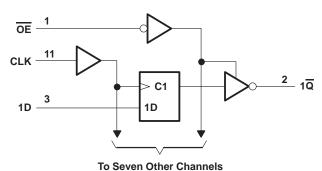
FUNCTION TABLE (each flip-flop)

	INPUTS	OUTPUT	
OE	CLK	D	Q
L	1	Н	L
L	\uparrow	L	н
L	H or L	Χ	\overline{Q}_0
Н	X	Χ	Z

logic symbol†



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1)		0.5 V to 7 V
Voltage range applied to any output in the high	or power-off state, VO	
Current into any output in the low state, IO: SN	54ABT534	96 mA
SN	74ABT534A	128 mA
Input clamp current, I _{IK} (V _I < 0)		–18 mA
Output clamp current, I _{OK} (V _O < 0)		
Package thermal impedance, θ_{JA} (see Note 2):	DB package	115°C/W
	DW package	97°C/W
	N package	67°C/W
	PW package	128°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero.



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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recommended operating conditions (see Note 3)

			SN54A	BT534	534 SN74ABT534A		UNIT
				MAX	MIN	MAX	UNII
Vcc	Supply voltage		4.5	5.5	4.5	5.5	V
VIH	High-level input voltage		2		2	2 V	
V _{IL}	V _{IL} Low-level input voltage			0.8		0.8	V
٧ _I	Input voltage		0	Vcc	0	VCC	V
loh	High-level output current			-24		-32	mA
loL	Low-level output current			48		64	mA
Δt/Δν	Input transition rise or fall rate	Outputs enabled		5		5	ns/V
T _A	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS		1	Γ _A = 25°(0	SN54ABT534		SN74ABT534A		UNIT	
PARAMETER		1E21 CONDITI	UNS	MIN	TYP [†]	MAX	MIN	MAX	MIN	MAX	ONIT
VIK	$V_{CC} = 4.5 \text{ V},$	$I_{ } = -18 \text{ mA}$				-1.2		-1.2		-1.2	V
	$V_{CC} = 4.5 \text{ V},$	$V_{CC} = 4.5 \text{ V}, I_{OH} = -3 \text{ mA}$		2.5			2.5		2.5		
Va	$V_{CC} = 5 \text{ V}, \qquad I_{OH} = -3$			3			3		3		v
VOH	V _{CC} = 4.5 V	I _{OH} = -24 m/	1	2			2				V
	VCC = 4.5 V	I _{OH} = -32 m/	١	2*					2		
Va	V45V	I _{OL} = 48 mA				0.55		0.55			V
VOL	V _{CC} = 4.5 V	I _{OL} = 64 mA				0.55*				0.55	V
V _{hys}					100						mV
lį	$V_{CC} = 5.5 V$,	V _I = V _{CC} or 0	SND			±1		±1		±1	μΑ
lozh	V _{CC} = 5.5 V, V _O = 2.7 V				10‡		10‡		10‡	μΑ	
lozL	$V_{CC} = 5.5 \text{ V}, V_{O} = 0.5 \text{ V}$				-10‡		-10 [‡]		-10‡	μΑ	
I _{off}	$V_{CC} = 0$,	V _I or V _O ≤ 4.5	5 V			±100				±100	μΑ
ICEX	V _{CC} = 5.5 V,	V _O = 5.5 V	Outputs high			50		50		50	μΑ
IO§	V _{CC} = 5.5 V,	V _O = 2.5 V		-50	-100	-180‡	-50	-180‡	-50	-180‡	mA
		_	Outputs high		1	250		250		250	μΑ
ICC	V _{CC} = 5.5 V, I _C V _I = V _{CC} or GI		Outputs low		24	30		30		30	mA
	AL = ACC OLGIAD		Outputs disabled		0.5	250		250		250	μΑ
ΔICC¶	V_{CC} = 5.5 V, One input at 3.4 V, Other inputs at V_{CC} or GND				1.5		1.5		1.5	mA	
C _i	V _I = 2.5 V or 0.5 V			3.5						pF	
Co	$V_0 = 2.5 \text{ V or } 0$	0.5 V			6.5						pF

^{*} On products compliant to MIL-PRF-38535, this parameter does not apply.



[†] All typical values are at $V_{CC} = 5 \text{ V}$.

[‡]This data sheet limit may vary among suppliers.

[§] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

						SN54ABT534				
				V _{CC} =	: 5 V, 25°C	MIN	MAX	UNIT		
				MIN	MAX					
fclock	Clock frequency				125		125	MHz		
t _W	Pulse duration	CL	K high or low	3.5		3.5		ns		
t _{su}	Setup time, data before CLK↑	Hig	gh or low	1.6		1.6		ns		
th	Hold time, data after CLK↑	Hig	gh or low	1.6		1.6		ns		

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

					SN74ABT534A			
			V _{CC} =	= 5 V, 25°C	MIN	MAX	UNIT	
			MIN	MAX				
fclock	Clock frequency			125		125	MHz	
t _W	Pulse duration	CLK high or low	3.5		3.5		ns	
t _{su}	Setup time, data before CLK↑	High or low	1.6		1.6		ns	
th	Hold time, data after CLK↑	High or low	2†		2†		ns	

[†]This data sheet limit may vary among suppliers.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50$ pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
f _{max}			125	175		125		MHz
^t PLH	CLK	Ια	2.6	4.5	6.1	2.6	7	ns
^t PHL		α	3.4	5.5	6.7	3.4	7.9	115
^t PZH	ŌĒ	Ια	1	3.4	5.2	1	5.8	ns
tPZL	OE	α	2.6	4	5.8	2.6	7	115
^t PHZ	ŌĒ	01	2.4	4.7	6.6	2.4	7.6	nc
^t PLZ	OE	Q	2.3	3.8	5.8	2.3	6.8	ns

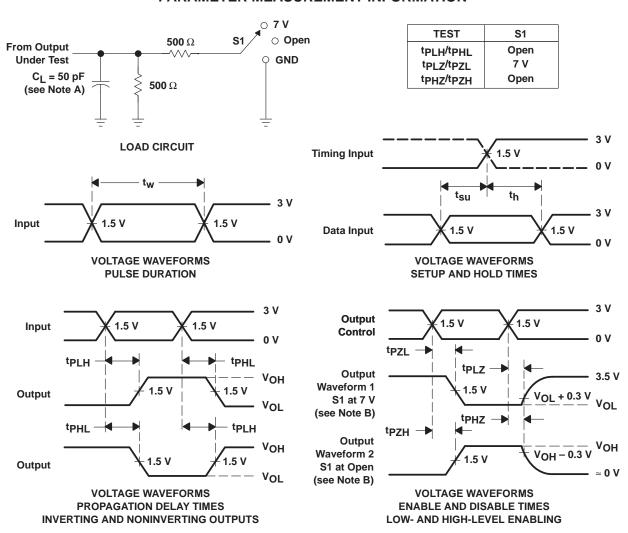
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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V ₍	CC = 5 \ \ = 25°C	/, ;	MIN	MAX	UNIT
			MIN	TYP	MAX	1		
f _{max}			125	175		125		MHz
^t PLH	CLK	Īα	2.6	4.5	5.9	2.6	6.7	ns
t _{PHL}		Q	3.4	5.5	6.7	3.4	7.6	115
^t PZH		Īα	1	3.4	4.2	1	5	ns
tPZL	ŌĒ	Q	2.6	4	5.8	2.6	6.8	115
^t PHZ	ŌĒ	Īα	2.4	4.7	6.6	2.4	7.3	ns
tPLZ	OE .	l u	2.3	3.8	5.8	2.3	6.5	115

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50~\Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns,
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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